

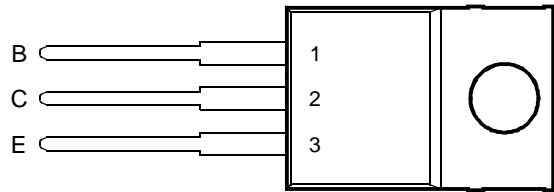
# BUL791 NPN SILICON POWER TRANSISTOR

Copyright © 1997, Power Innovations Limited, UK

JULY 1991 - REVISED SEPTEMBER 1997

- **Designed Specifically for High Frequency Electronic Ballasts up to 125 W**
- **$h_{FE}$  6 to 22 at  $V_{CE} = 1\text{ V}$ ,  $I_C = 2\text{ A}$**
- **Low Power Losses (On-state and Switching)**
- **Key Parameters Characterised at High Temperature**
- **Tight and Reproducible Parametric Distributions**

**TO-220 PACKAGE  
(TOP VIEW)**



Pin 2 is in electrical contact with the mounting base.

MDTRACA

### absolute maximum ratings at 25°C ambient temperature (unless otherwise noted)

RATING	SYMBOL	VALUE	UNIT
Collector-emitter voltage ( $V_{BE} = 0$ )	$V_{CES}$	700	V
Collector-base voltage ( $I_E = 0$ )	$V_{CBO}$	700	V
Collector-emitter voltage ( $I_B = 0$ )	$V_{CEO}$	400	V
Emitter-base voltage	$V_{EBO}$	9	V
Continuous collector current	$I_C$	4	A
Peak collector current (see Note 1)	$I_{CM}$	8	A
Peak collector current (see Note 2)	$I_{CM}$	14	A
Continuous base current	$I_B$	2.5	A
Peak base current (see Note 2)	$I_{BM}$	3.5	A
Continuous device dissipation at (or below) 25°C case temperature	$P_{tot}$	75	W
Operating junction temperature range	$T_j$	-65 to +150	°C
Storage temperature range	$T_{stg}$	-65 to +150	°C

NOTES: 1. This value applies for  $t_p = 10\text{ ms}$ , duty cycle  $\leq 2\%$ .  
 2. This value applies for  $t_p = 300\text{ }\mu\text{s}$ , duty cycle  $\leq 2\%$ .

## PRODUCT INFORMATION

Information is current as of publication date. Products conform to specifications in accordance with the terms of Power Innovations standard warranty. Production processing does not necessarily include testing of all parameters.



# BUL791

## NPN SILICON POWER TRANSISTOR

JULY 1991 - REVISED SEPTEMBER 1997

### electrical characteristics at 25°C case temperature (unless otherwise noted)

PARAMETER	TEST CONDITIONS	MIN	TYP	MAX	UNIT
$V_{CEO(sus)}$ Collector-emitter sustaining voltage	$I_C = 100\text{ mA}$ $L = 25\text{ mH}$ (see Note 3)	400			V
$I_{CES}$ Collector-emitter cut-off current	$V_{CE} = 700\text{ V}$ $V_{BE} = 0$ $V_{CE} = 700\text{ V}$ $V_{BE} = 0$ $T_C = 90^\circ\text{C}$			10 200	$\mu\text{A}$
$I_{EBO}$ Emitter cut-off current	$V_{EB} = 9\text{ V}$ $I_C = 0$			1	mA
$V_{BE(sat)}$ Base-emitter saturation voltage	$I_B = 400\text{ mA}$ $I_C = 2\text{ A}$ (see Notes 4 and 5) $I_B = 400\text{ mA}$ $I_C = 2\text{ A}$ $T_C = 90^\circ\text{C}$		0.94 0.86	1	V
$V_{CE(sat)}$ Collector-emitter saturation voltage	$I_B = 400\text{ mA}$ $I_C = 2\text{ A}$ (see Notes 4 and 5) $I_B = 400\text{ mA}$ $I_C = 2\text{ A}$ $T_C = 90^\circ\text{C}$		0.25 0.3	0.4	V
$h_{FE}$ Forward current transfer ratio	$V_{CE} = 1\text{ V}$ $I_C = 10\text{ mA}$ $V_{CE} = 1\text{ V}$ $I_C = 2\text{ A}$ $V_{CE} = 5\text{ V}$ $I_C = 8\text{ A}$	10 6 2	16.5 12 6.5	22 14	
$V_{FCB}$ Collector-base forward bias diode voltage	$I_{CB} = 60\text{ mA}$		850		mV

NOTES: 3. Inductive loop switching measurement.

4. These parameters must be measured using pulse techniques,  $t_p = 300\ \mu\text{s}$ , duty cycle  $\leq 2\%$ .

5. These parameters must be measured using voltage-sensing contacts, separate from the current carrying contacts, and located within 3.2 mm from the device body.

### thermal characteristics

PARAMETER	MIN	TYP	MAX	UNIT
$R_{\theta JA}$ Junction to free air thermal resistance			62.5	$^\circ\text{C}/\text{W}$
$R_{\theta JC}$ Junction to case thermal resistance			1.66	$^\circ\text{C}/\text{W}$

### inductive-load switching characteristics at 25°C case temperature

PARAMETER	TEST CONDITIONS	MIN	TYP	MAX	UNIT
$t_{sv}$ Storage time	$I_C = 2\text{ A}$ $I_{B(on)} = 400\text{ mA}$ $V_{CC} = 40\text{ V}$ $L = 1\text{ mH}$ $I_{B(off)} = 800\text{ mA}$ $V_{CLAMP} = 300\text{ V}$		2.2	3	$\mu\text{s}$
$t_{fi}$ Current fall time			95	180	ns
$t_{xo}$ Cross over time				210	300
$t_{sv}$ Storage time	$I_C = 2\text{ A}$ $I_{B(on)} = 400\text{ mA}$ $V_{CC} = 40\text{ V}$ $L = 1\text{ mH}$ $I_{B(off)} = 250\text{ mA}$ $V_{CLAMP} = 300\text{ V}$		4	6	$\mu\text{s}$
$t_{fi}$ Current fall time			120	230	ns

### resistive-load switching characteristics at 25°C case temperature

PARAMETER	TEST CONDITIONS	MIN	TYP	MAX	UNIT
$t_{sv}$ Storage time	$I_C = 2\text{ A}$ $I_{B(on)} = 400\text{ mA}$ $V_{CC} = 300\text{ V}$ $I_{B(off)} = 400\text{ mA}$		2.2	3	$\mu\text{s}$
$t_{fi}$ Current fall time			160	250	ns

TYPICAL CHARACTERISTICS

FORWARD CURRENT TRANSFER RATIO  
vs  
COLLECTOR CURRENT

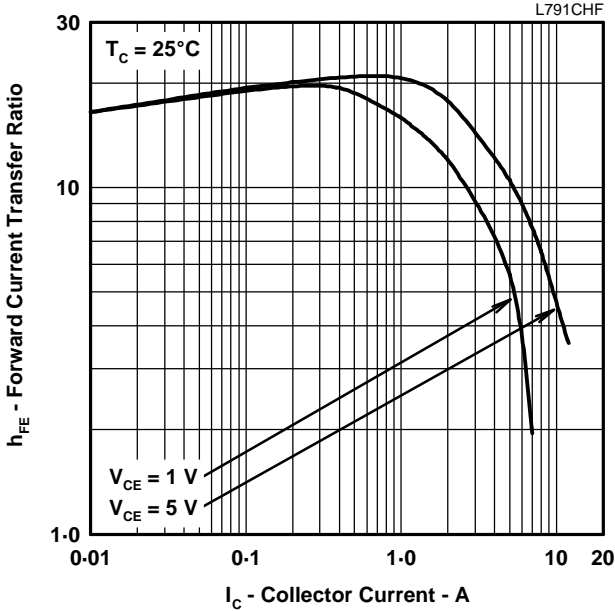


Figure 1.

COLLECTOR-EMITTER SATURATION VOLTAGE  
vs  
COLLECTOR CURRENT

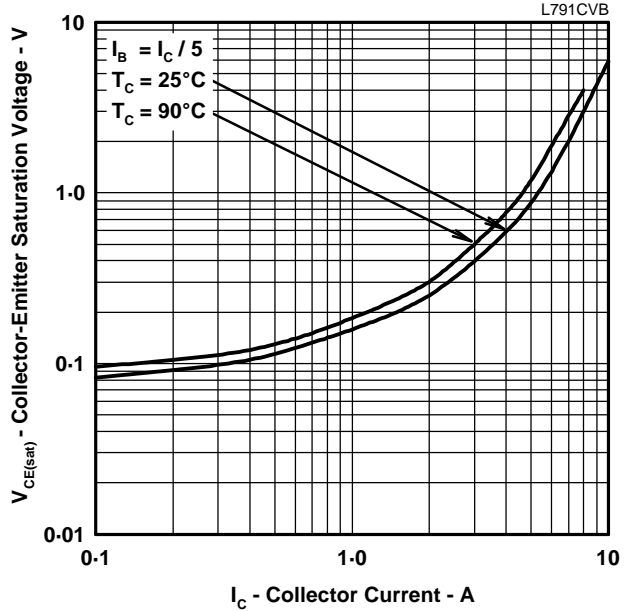


Figure 2.

INDUCTIVE SWITCHING TIMES  
vs  
COLLECTOR CURRENT

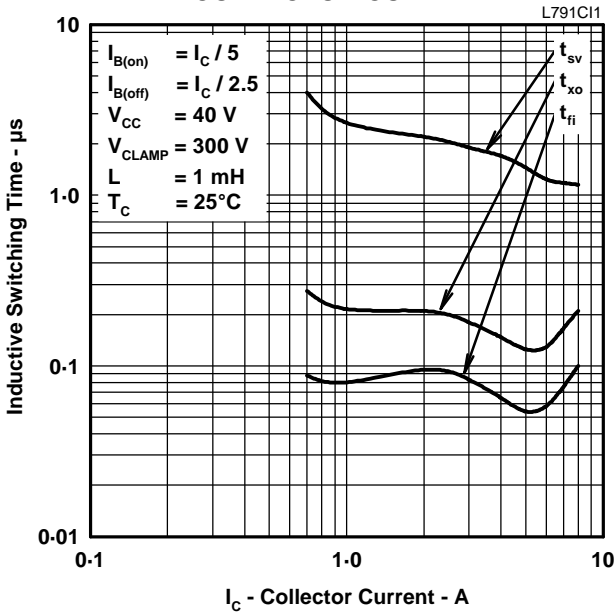


Figure 3.

INDUCTIVE SWITCHING TIMES  
vs  
CASE TEMPERATURE

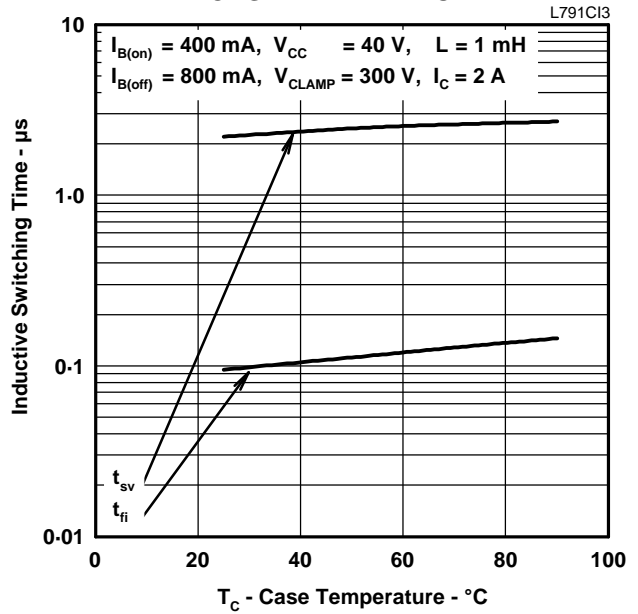


Figure 4.

# BUL791 NPN SILICON POWER TRANSISTOR

JULY 1991 - REVISED SEPTEMBER 1997

## TYPICAL CHARACTERISTICS

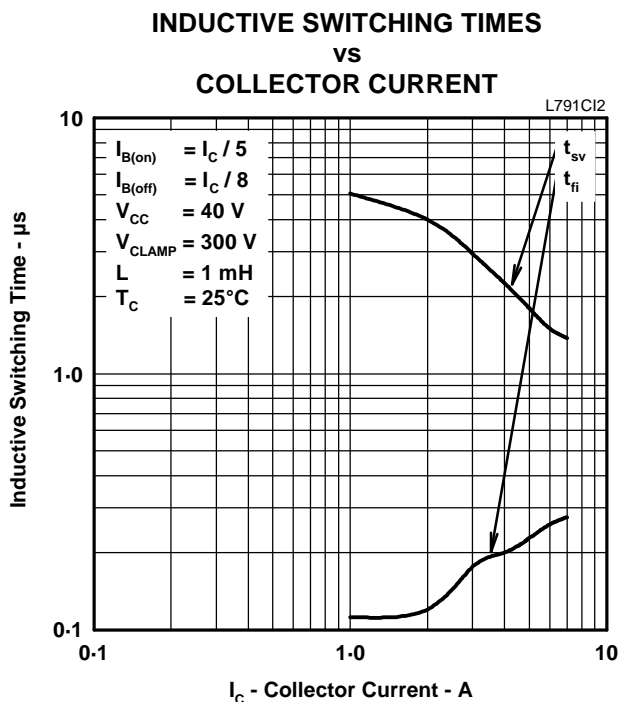


Figure 5.

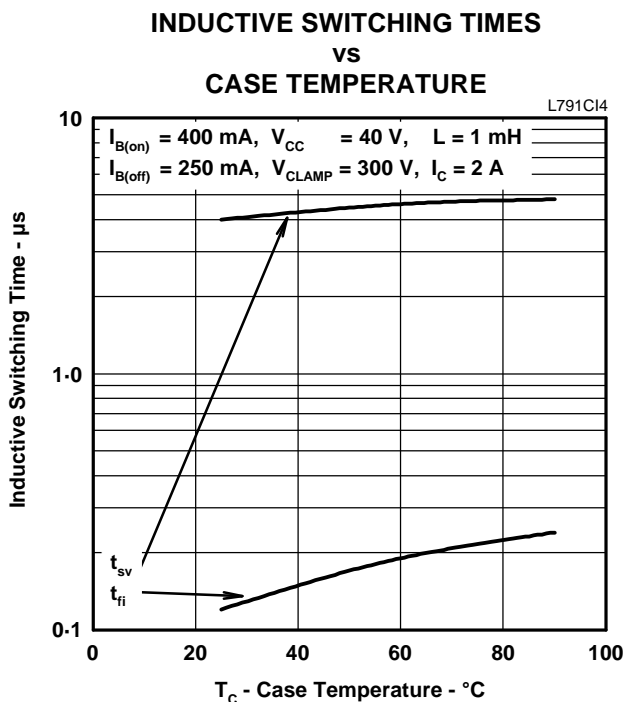


Figure 6.

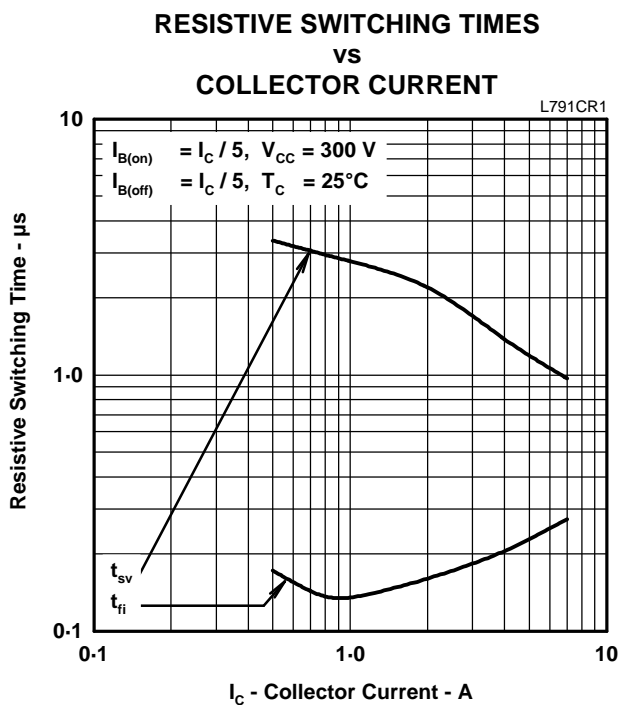


Figure 7.

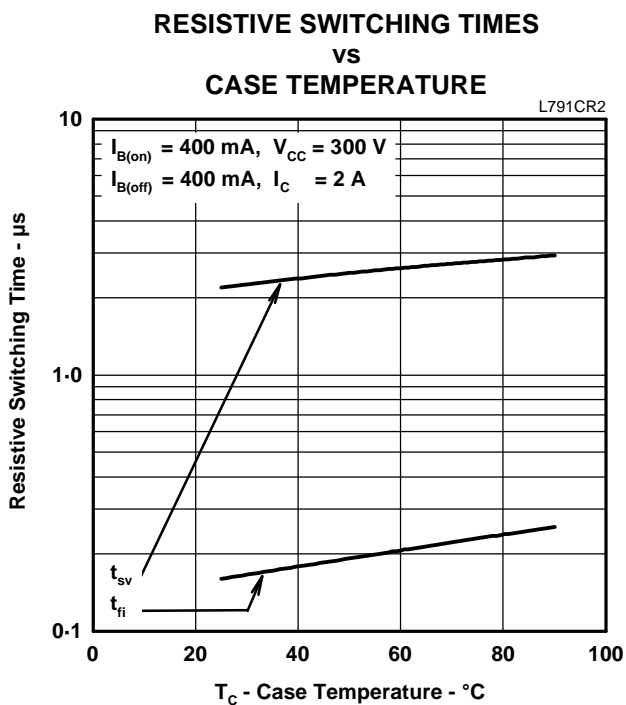


Figure 8.

MAXIMUM SAFE OPERATING REGIONS

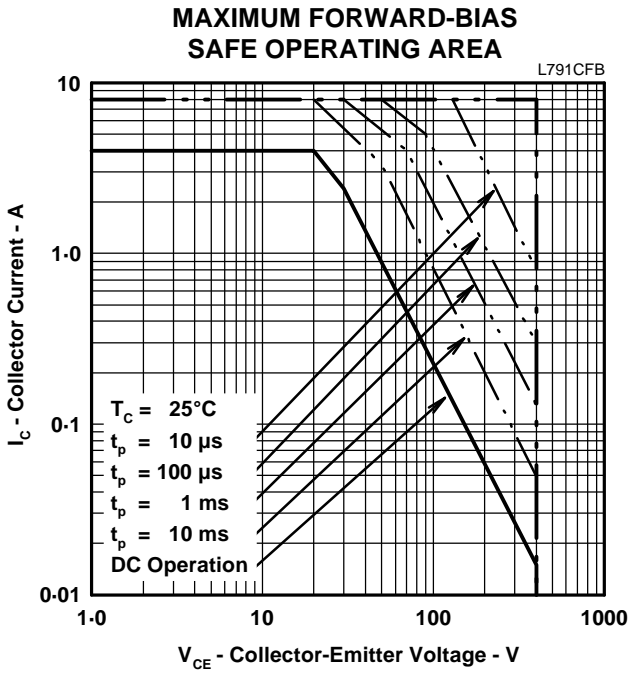


Figure 9.

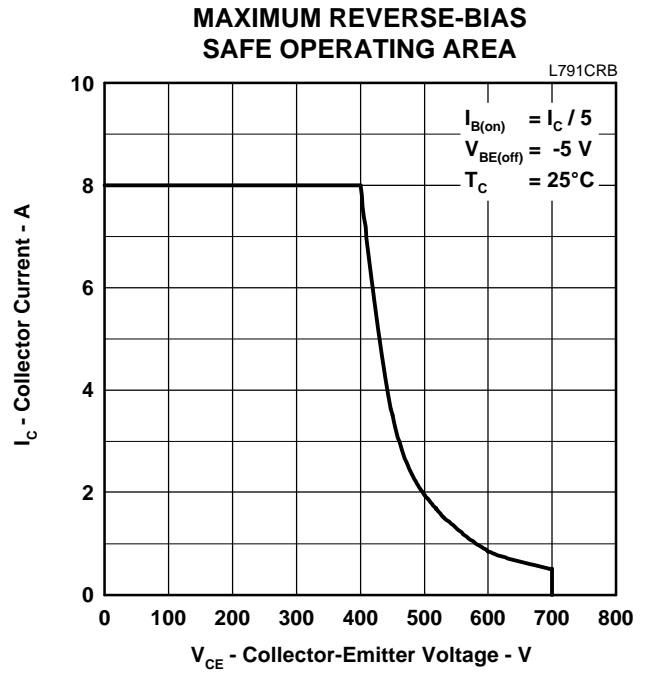


Figure 10.

# BUL791 NPN SILICON POWER TRANSISTOR

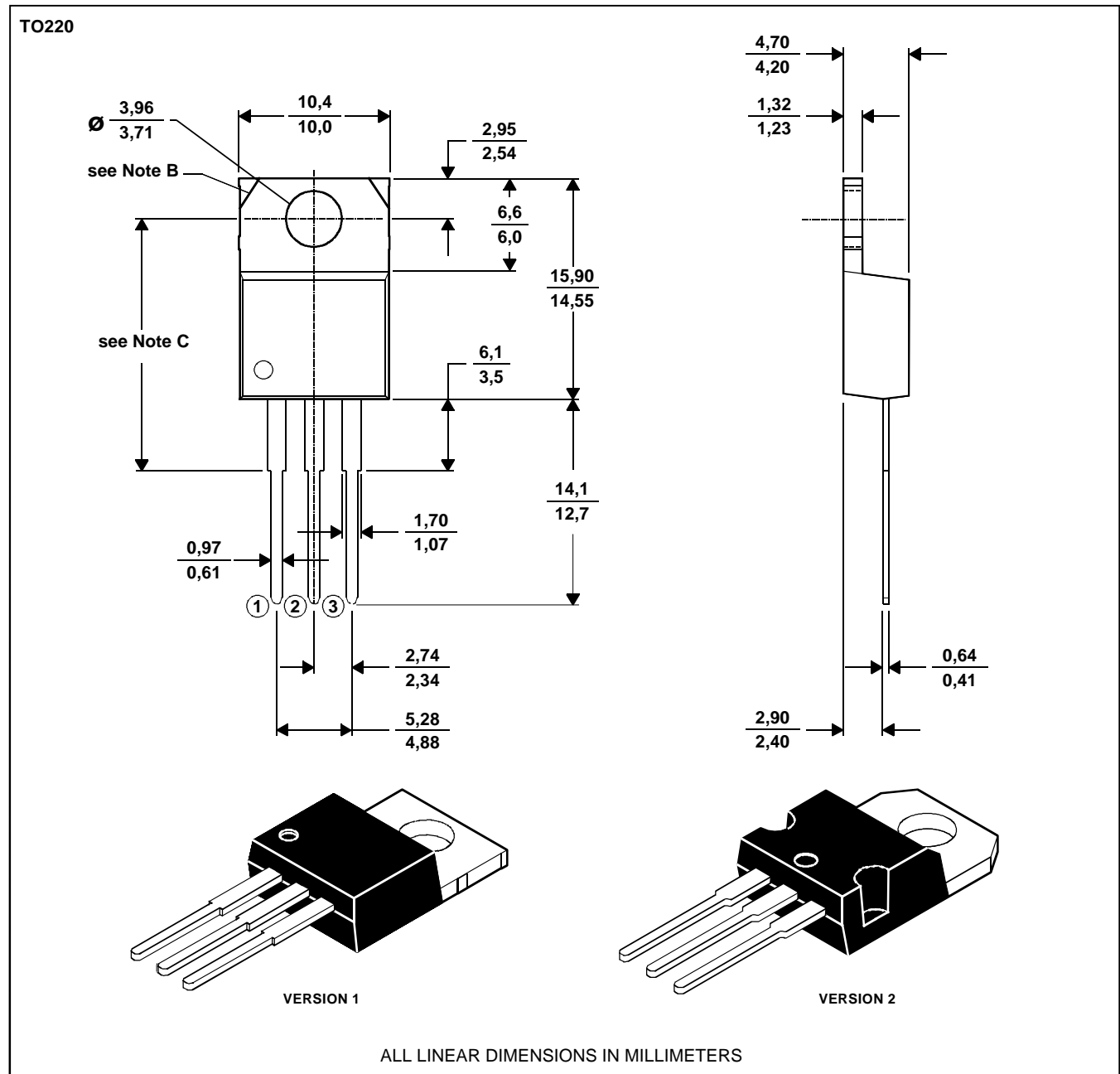
JULY 1991 - REVISED SEPTEMBER 1997

## MECHANICAL DATA

### TO-220

#### 3-pin plastic flange-mount package

This single-in-line package consists of a circuit mounted on a lead frame and encapsulated within a plastic compound. The compound will withstand soldering temperature with no deformation, and circuit performance characteristics will remain stable when operated in high humidity conditions. Leads require no additional cleaning or processing when used in soldered assembly.



- NOTES: A. The centre pin is in electrical contact with the mounting tab.  
 B. Mounting tab corner profile according to package version.  
 C. Typical fixing hole centre stand off height according to package version.  
 Version 1, 18.0 mm. Version 2, 17.6 mm.

MDXXBE

## PRODUCT INFORMATION

### **IMPORTANT NOTICE**

Power Innovations Limited (PI) reserves the right to make changes to its products or to discontinue any semiconductor product or service without notice, and advises its customers to verify, before placing orders, that the information being relied on is current.

PI warrants performance of its semiconductor products to the specifications applicable at the time of sale in accordance with PI's standard warranty. Testing and other quality control techniques are utilized to the extent PI deems necessary to support this warranty. Specific testing of all parameters of each device is not necessarily performed, except as mandated by government requirements.

PI accepts no liability for applications assistance, customer product design, software performance, or infringement of patents or services described herein. Nor is any license, either express or implied, granted under any patent right, copyright, design right, or other intellectual property right of PI covering or relating to any combination, machine, or process in which such semiconductor products or services might be or are used.

PI SEMICONDUCTOR PRODUCTS ARE NOT DESIGNED, INTENDED, AUTHORIZED, OR WARRANTED TO BE SUITABLE FOR USE IN LIFE-SUPPORT APPLICATIONS, DEVICES OR SYSTEMS.

Copyright © 1997, Power Innovations Limited